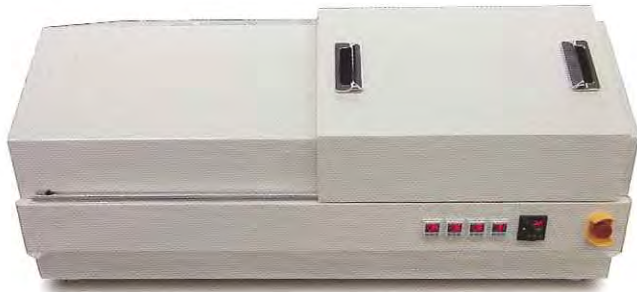


# Resistivity Measuring Instrument



## RT-3000/RG-180

- Up to 18" (460mm)  $\phi$  automatic probing unit
- High stable measurement in the range of  $1\text{m}\Omega \cdot \text{cm} \sim 10\text{M}\Omega \cdot \text{cm}$
- High accurate dual configuration measurement and Self-test function
- No limits point of 2-D, 3-D mapping measurement
- Flexible measurement sites programmable
- Single (standard) and dual measurement modes
- Standard resistor accuracy :  $\leq \pm 0.1\%$  ( $1\text{m}\Omega \sim 1\text{M}\Omega$ )
- NIST standard wafers :  $\leq \pm 1.0\%$  ( $23^\circ\text{C}$ )
- NIST standard repeatability :  $\leq 0.2\%$  ( $\sigma$ )

### APPLICATIONS

Silicon wafer and various types of semiconductor layer, and CMP process

### DIMENSIONS

1,120 (W)  $\times$  640 (D)  $\times$  450 (H) mm  
approx. 125kg (PC is not included)

### UTILITIES

Power supply : \*Select from 100~240V, 50/60Hz, 1kVA  
Vacuum :  $-86\text{kPa}$



## RG-200PV

- High stable measurement in the range of  $1\text{m}\Omega / \square \sim 10,000\text{k} (10\text{M}) \Omega / \square$
- High accurate dual configuration measurement and Self-test function
- X-Y multi patterns with 0.1mm resolution and 2-D, 3-D mapping measurement
- High speed and high tact performance ( $36\text{sites} \leq 60\text{sec}$ )
- Single (standard) and dual measurement modes
- Standard resistor accuracy :  $\leq \pm 0.1\%$  ( $1\text{m}\Omega \sim 1\text{M}\Omega$ )
- NIST standard wafers :  $\leq \pm 1.0\%$  ( $23^\circ\text{C}$ )
- NIST standard repeatability :  $\leq 0.2\%$  ( $\sigma$ )
- PN type check function (option)

### APPLICATIONS

Silicon solar cell / wafer 156mm  $\times$  156mm or less, thickness  $100\mu\text{m} \sim 5\text{mm}$  (300mm  $\times$  300mm or other sizes X-Y probing stage is available with Model RG-100)

### DIMENSIONS

400 (W)  $\times$  600 (D)  $\times$  325 (H) mm plus PC  
approx. 35kg (PC is not included)

### UTILITIES

Power supply : \*Select from 100~240V, 50/60Hz, 300VA  
Vacuum :  $-86\text{kPa}$

## DF-9P

- 9 sites measurement in 7 seconds for solar cell

